

EddyCus® TF lab 4040A – Anisotropy Tester

P T 4040A 21



Highlights

- ► Contact-free and real time
- ► Accurate single-point measurement
- Manual mapping guided by easy-tohandle software
- ► Measurement of encapsulated layers
- Characterization of multilayer materials upon request

Applications

- ► Touch panel sensors (TPS)
- ► Printed electronics
- ▶ Wearable electronics
- ► Smart textiles
- ► Photovoltaics
- ► Smart / switchable films
- ► Medical surfaces and devices
- ► Biological sensors
- ► Aerospace, automotive, transportation
- ► Semiconductor and memory
- ► Energy storage

Device Series

- Metal thickness (nm, μm)
- ► Sheet resistance (Ohm/sq)
- Emissivity
- ► Transmittance, reflectance, haze
- ► Conductivity / resistivity (mOhm cm)
- ► Electrical anisotropy (%)
- ▶ Weight (g/m²) and drying status (%)
- ▶ Permeability (H/m) Beta

Materials

- ► Nanowire films
 - ► Conductive NW (Ag, Ni, Pt, Au)
 - ► Semiconductor NW (Si, SiC)
 - ► Magnetic NW (Fe₃O₄-AgNWs)
 - ► Multilayer NW (ZnO/AgNW/ZnO)
- ► Carbon Nano Tubes and Buds
- ► Fiber reinforced composites
- ► Metal meshes, smart meshes
- ► Anisotropic grain / domain materials
- Anisotropic effect / defect directions (cracks, line defects)

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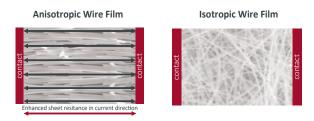
Engineered and Made in Germany



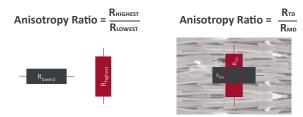


Anisotropy Term and Concept

- ► Electrical anisotropy refers to a difference in electrical resistance depending on the direction of current flow
- ▶ Wire and mesh structures can have anisotropic resistances
- Bulk materials with dominant directional characteristics / effects / defects can also have electrical anisotropy
- ► Anisotropy can be optimized to the layout of the contacts
- Anisotropy can save material and improve optical transparency to sheet resistance ratio



- ▶ Described by anisotropy direction and strength
- ▶ Both characteristics must be obtained at the same position
- ► The anisotropy strength is calculated using the lowest and highest resistance that align in perpendicular directions
- ► Inline deposition, e.g. slot die coating on moving web, tends to create lower resistances in machine direction "MD" and higher resistance in traversing direction "TD"
- ► Calculation as ratio of lowest and highest resistance



Device Characteristics

| Measurement technology | Non-contact eddy current sensor with directed current induction |
|------------------------------------|--|
| Substrates | Foils, glass, wafer, etc. |
| Substrate area | 29.5" x 25.6" / 750 mm x 650 mm (for 400 mm x 400 mm samples) |
| Max. sample thickness / sensor gap | 3/5/10/25 mm (defined by the thickest sample) |
| Sheet resistance range | 0.01 – 1,000 Ohm/sq; 1 to 5 % accuracy |
| Anisotropy range (TD/MD) | 0.33 – 3 (larger upon request) |
| Device dimensions (w/h/d) / weight | 30" x 12" x 26" / 760 mm x 310 mm x 660 mm / 20 kg |
| Further available features | Metal thickness, optical transmittance and reflectance, sheet resistance, emissivity, resistivity and anisotropy measurement |

Device Control and Software

